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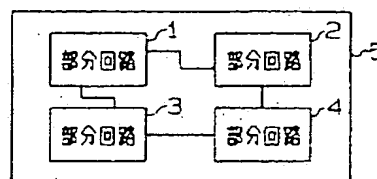
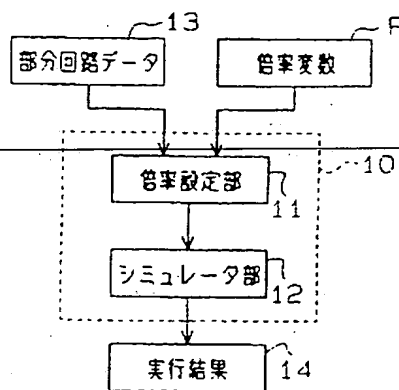
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 H01L 21/66

TITLE : SIMULATION METHOD FOR  
 SEMICONDUCTOR INTEGRATED  
 CIRCUIT



ABSTRACT : PURPOSE: To realize the promotion of the efficiency of simulation by multiplying every partial circuit by the scale factor variable of an optional value.

CONSTITUTION: A simulation device 10 is constituted by being provided with a scale factor setting part 11 and a simulation part 12, and the partial circuit data 13 of every partial circuit 1 to 4 is inputted to the scale factor setting part 11. Then, every partial circuit 1 to 4 is multiplied by the scale factor variable P of the optional value. Thus, the element constants of all basic elements to constitute the partial circuits 1 to 4 are changed, and an electric characteristic similar to the electric characteristic in the case the partial circuits 1 to 4 are connected in parallel is obtained, and the efficiency of the simulation of a semiconductor integrated circuit is promoted.

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